

OptiMOS[™]-5 **Power-Transistor**





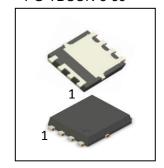
Product Summary

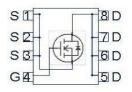
V _{DS}	40	V
$R_{\mathrm{DS(on),max}}$	4.2	mΩ
I _D	70	Α

Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Logic Level
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

PG-TDSON-8-33





Туре	Package	Marking
IPC70N04S5L-4R2	PG-TDSON-8-33	5N04L4R2

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	I _D	T _C =25 °C, V _{GS} =10 V	70	А
		$T_{\rm C}$ =100°C, $V_{\rm GS}$ =10 $V^{2)}$	53	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25°C	280	
Avalanche energy, single pulse ²⁾	E _{AS}	I _D =35A	32	mJ
Avalanche current, single pulse ⁴⁾	I _{AS}	-	70	А
Gate source voltage	V_{GS}	-	±16	V
Power dissipation	P_{tot}	T _C =25°C	50	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	3.0	K/W
Thermal resistance, junction - ambient	R_{thJA}	6 cm ² cooling area ³⁾	-	-	50	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS}$ =0V, $I_{\rm D}$ = 1mA	40	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{\rm DS} = V_{\rm GS}$, $I_{\rm D} = 17 \mu A$	1.2	1.6	2.0	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	-	-	1	μΑ
		$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾	-	-	100	
Gate-source leakage current	I_{GSS}	V _{GS} =16V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =4.5V, I _D =35A	-	4.4	6.1	mΩ
		V _{GS} =10V, I _D =35A	-	3.4	4.2	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	C_{iss}		-	1230	1600	pF
Output capacitance	Coss	V _{GS} =0V, V _{DS} =25V, f=1MHz	-	280	364]
Reverse transfer capacitance	C _{rss}		-	20	30	
Turn-on delay time	$t_{d(on)}$		-	3	-	ns
Rise time	tr	V _{DD} =20V, V _{GS} =10V,	-	2	-	<u> </u>
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =70A, $R_{\rm G,ext}$ =3.5 Ω	-	11	-	
Fall time	t_{f}		-	6	-	
Gate Charge Characteristics ²⁾	_		1	,		1
Gate to source charge	Q _{gs}			3.5	4.6	nC
Gate to drain charge	Q _{gd}	$V_{\rm DD}$ =32V, $I_{\rm D}$ =70A, $V_{\rm GS}$ =0 to 10V		4.7	7.1	
Gate charge total	Qg		-	22	30	
Gate plateau voltage	$V_{ m plateau}$		-	3	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T -25°C	-	-	70	А
Diode pulse current ²⁾	I _{S,pulse}	− <i>T</i> _C =25°C	-	-	280	
Diode forward voltage	V _{SD}	V _{GS} =0V, I _F =35A, T _j =25°C	-	0.8	1.1	V
Reverse recovery time ²⁾	t _{rr}	V_{R} =20V, I_{F} =50A, di_{F}/dt =100A/ μ s	-	30	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	18	-	nC

 $^{^{1)}}$ Current is limited by package; with an $R_{\rm thJC}$ = 3K/W the chip is able to carry 75A at 25°C.

²⁾ The parameter is not subject to production test- verified by design/characterization.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

⁴⁾ The device is tested in production with an avalanche current of 60 A.

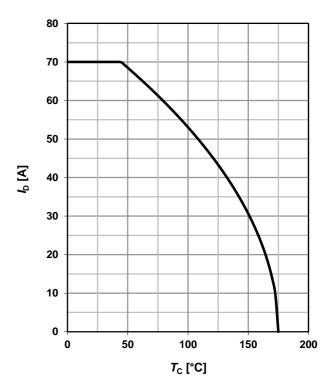


1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} = 10 \text{ V}$$

2 Drain current

$$I_{\rm D} = f(T_{\rm C}); \ V_{\rm GS} = 10 \ {\rm V}$$



3 Safe operating area

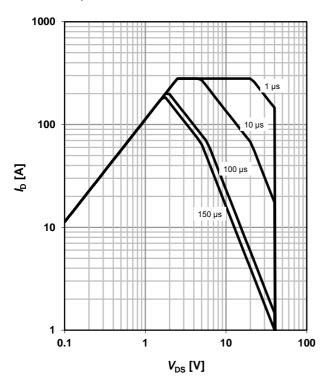
$$I_{\rm D} = {\rm f}(V_{\rm DS}); T_{\rm C} = 25 \,{\rm ^{\circ}C}; D = 0$$

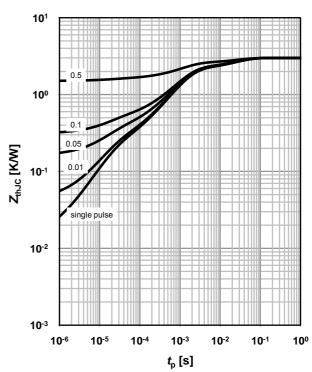
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D=t_p/T$



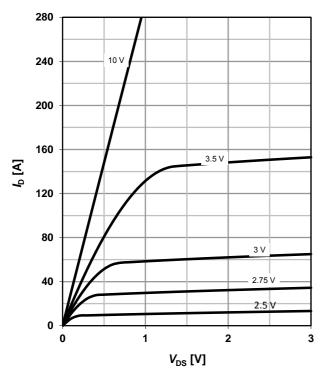




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$

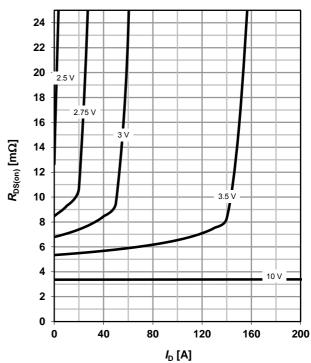
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 °C$

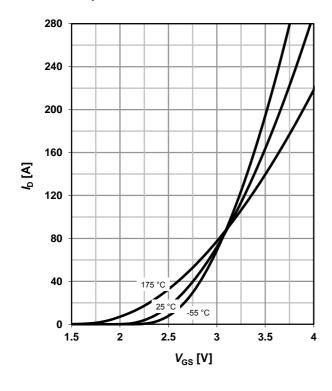
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

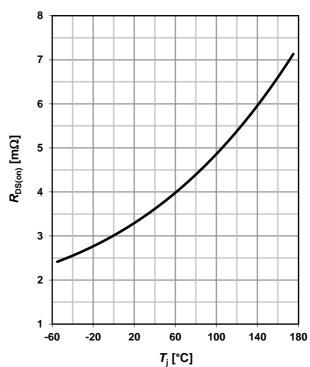
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 35 \text{ A}; V_{GS} = 10 \text{ V}$$





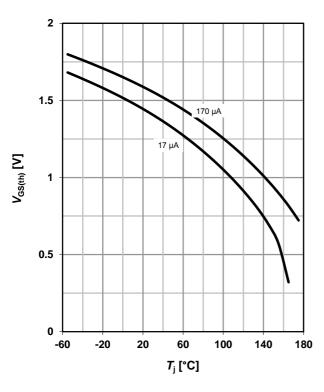
9 Typ. gate threshold voltage

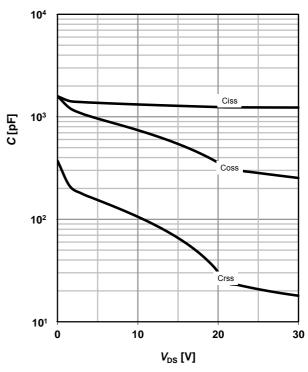
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristics

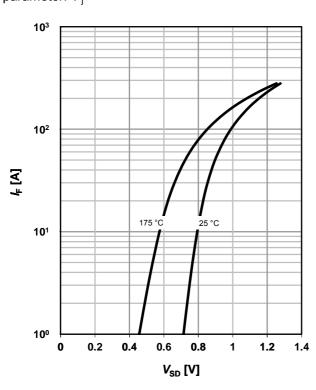
 $IF = f(V_{SD})$

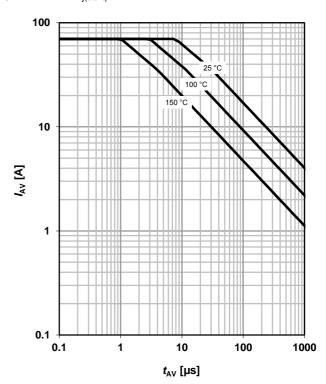
parameter: T_i

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}





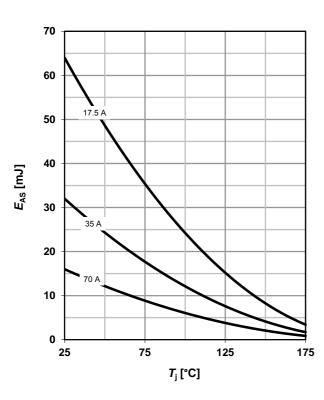


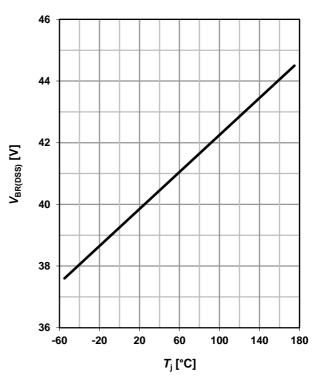
13 Avalanche energy

$E_{AS} = f(T_j)$

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

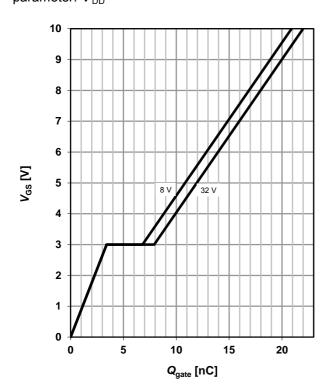




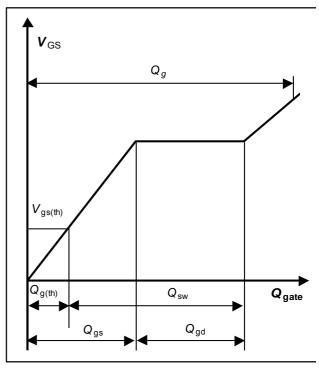
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 70 A pulsed$

parameter: $V_{\rm DD}$



16 Gate charge waveforms





Published by Infineon Technologies AG 81726 Munich, Germany

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Revision History

Version	Date	Changes		
Revision 1.0	06.12.2016	Final Data Sheet		